## Department of Electrical Engineering Indian Institute of Technology, Kanpur

## EE 210Microelectronics-I2017-18-II

Schedule: Lectures: 10:00 AM – 11:00 AM MWF (L1) Tutorials: 10:00 AM – 11:00 AM Tu (TB103-TB106)

Text: Semiconductor Devices and Circuits, Aloke Dutta, Oxford University Press, 2008

## **References:** \* Analysis and Design of Analog Integrated Circuits; P.R. Gray, P.J. Hurst, S.H. Lewis, and R.G. Meyer; John Wiley & Sons, 4<sup>th</sup> Edition, 2001

- \* MOS Analog Circuits for Signal Processing; R. Gregorian and G.C. Temes; John Wiley & Sons, 1986
- \* Microelectronic Circuits; A.S. Sedra and K.C. Smith; Oxford University Press, 5<sup>th</sup> Edition, 2004
- \* Microelectronics; J. Millman and A. Grabel; McGraw-Hill, 2<sup>nd</sup> Edition, 1987
- Instructor: Aloke Dutta, WL 126, 7661, aloke
- **Tutors:** S.S.K. Iyer (WL 122, 7820, sskiyer), S. Qureshi (WL 211, 7133, qureshi), A. Verma (WL 132, 6432, amitkver), and Aloke Dutta
- **Topics:** 1. I-V Characteristics and small-signal models of basic semiconductor devices (diodes, BJTs, and MOSFETs)
  - 2. Biasing
  - 3. Amplifiers
  - 4. Output stages
  - 5. Low- and high-frequency responses of amplifiers
  - 6. Stability and compensation of amplifiers
  - 7. Operational amplifiers
- Grading: Tutorial Assessment (Mini-Quizzes) 15% 2 Quizzes (30<sup>th</sup> January and 27<sup>th</sup> March) – 15% Mid-Sem – 30% End-Sem – 40%
- **Note:** All course related material will be posted in Brihaspati No make-up for any mini-quiz under any circumstances For main quizzes and exams, make-up may be allowed only under medical emergency

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